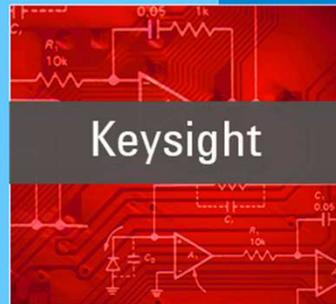


INTEGRIDAD DE SEÑAL

Analizador PCB – Altas Prestaciones, Bajo Coste



Héctor Carreño

Application Engineer
hector_carreno@agilent.com

Need help?
contactcenter_spain@agilent.com
91 631 3300

AGENDA



Unlocking Measurement Insights for 75 Years

- Traditional PCB Measurements
- PCB Market Trends
- Dedicated VNA for PCB Measurements
- Summary & Closure

AGENDA



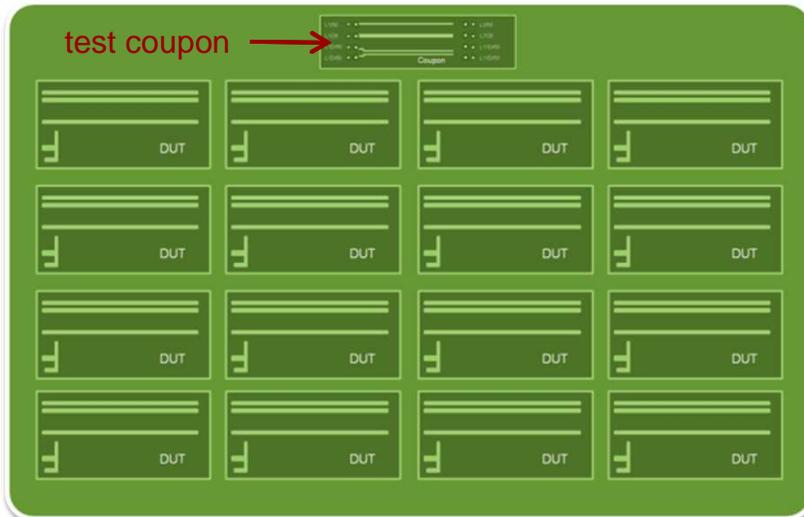
Unlocking Measurement Insights for 75 Years

- **Traditional PCB Measurements**
- PCB Market Trends
- Dedicated VNA for PCB Measurements
- Summary & Closure

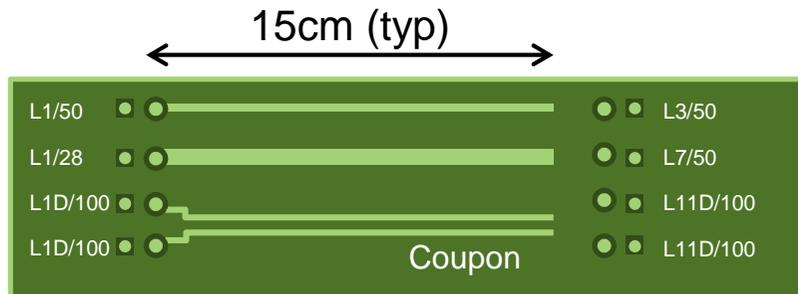
Traditional PCB Measurements



Unlocking Measurement Insights for 75 Years

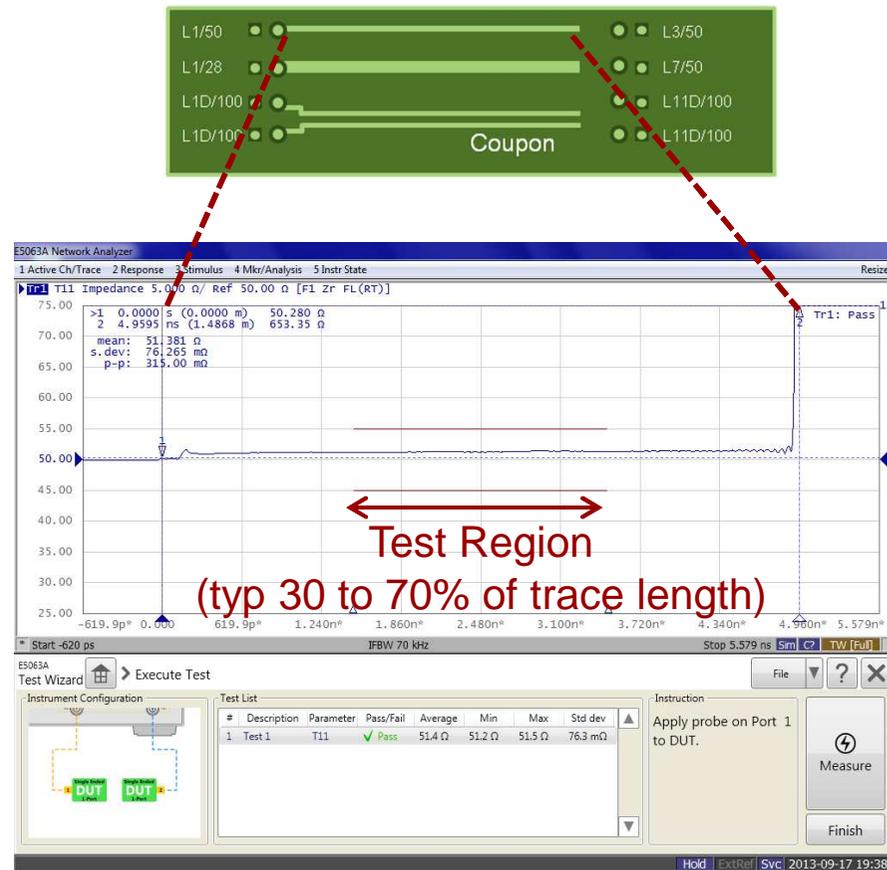


•Test Coupon Example:



- Parameters = Impedance (SE & DIFF)
- Required Tolerance = $\pm 10\%$

•L1/50 trace measurement example



Manual Procedure on VNA



Unlocking Measurement Insights for 75 Years

- ✓ Set Time Domain Parameters
 - Stimulus to Low Pass Step
 - Set Freq Low Pass
- ✓ Calibrate
- ✓ Fixture Compensation
- ✓ Enable Fixture Simulator: BalUn, Diff Z, Z Conv
- ✓ Enable Time Transform
- ✓ Format Lin Mag
- ✓ MRK1 Search Target 0.5 (probe open)
- ✓ MRK2 Search Target 0.5 (probe measuring)
- ✓ Set MEAS RANGE from 30%MRK1 to 70%MRK2
- ✓ Enable LIMIT TEST

L1D/100 trace measurement example



AGENDA



Unlocking Measurement Insights for 75 Years

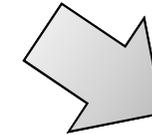
- Traditional PCB Measurements
- **PCB Market Trends**
- Dedicated VNA for PCB Measurements
- Summary & Closure

PCB Market Trends



Unlocking Measurement Insights for 75 Years

PCB



Antenna

Trends:

- Higher data rates
- Tighter impedance control

Measurements:

- Impedance (TDR)
- Sample or 100% testing
- Required tolerance = $\pm 5\%$
- In-circuit test (non-coupon)

⇒ Need more accurate and higher bandwidth instrument

Trends:

- More PCB integrated antennas
- More PCB suppliers manufacture antennas

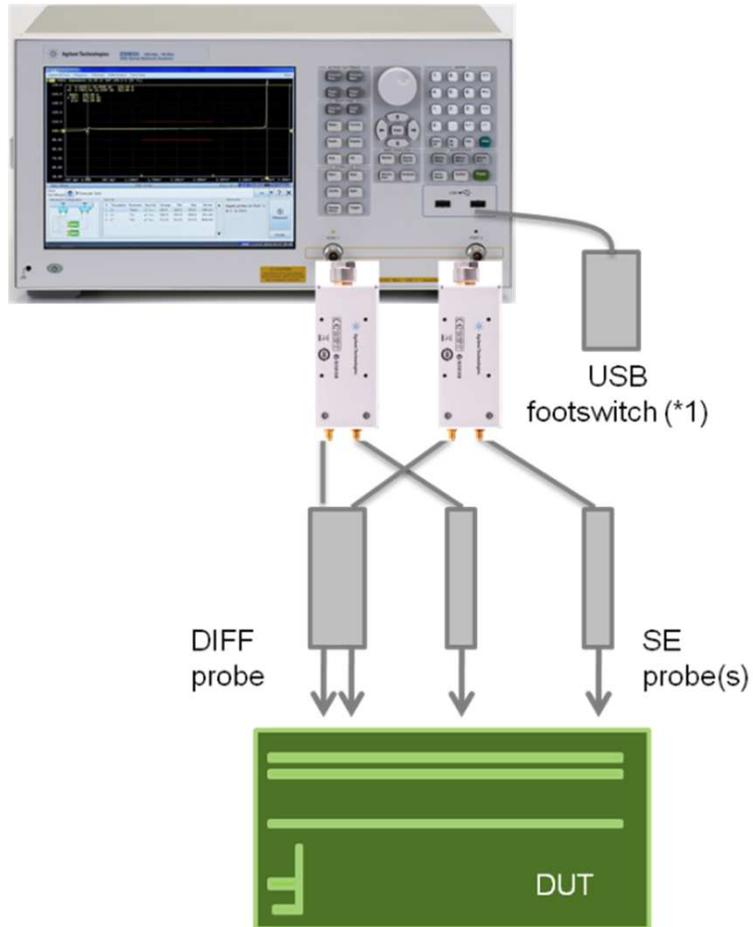
Measurements:

- Return loss (S-parameters)
- 100% testing

⇒ Need to measure in both time and frequency domains

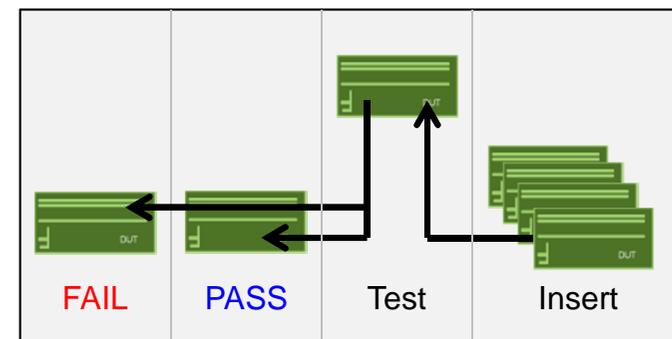
Use Models

Manual Testing



Automated Testing

Unlocking Measurement Insights for 75 Years



AGENDA



Unlocking Measurement Insights for 75 Years

- Traditional PCB Measurements
- PCB Market Trends
- **Dedicated VNA for PCB Measurements**
- Summary & Closure

E5063A PCB Analyzer



Unlocking Measurement Insights for 75 Years

The Best Solution for PCB Manufacturing Test



- Frequency Range 4.5/8.5/18 GHz
- Number of Ports 2 or 4 w/ switch U1810B
- Time Domain YES
- Frequency Domain YES
- Topology SE & DIFF
- PCB Dedicated GUI YES
- Error Correction Deskew, Deskew&Loss, and Electronic Cal
- ESD Robustness YES

- **More Accuracy and R&R***
- **More ESD Robustness**
- **Dedicated GUI for PCB Measurements**
- **The lowest cost solution in the industry**

* Repeatability & Reproducibility

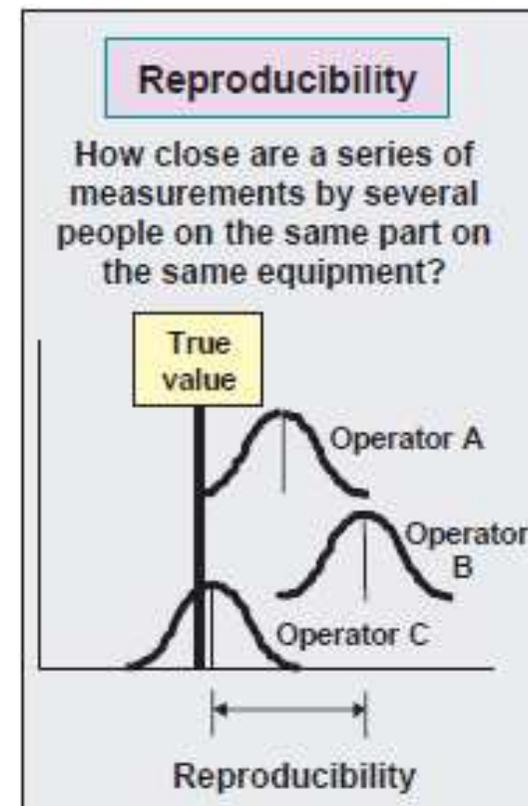
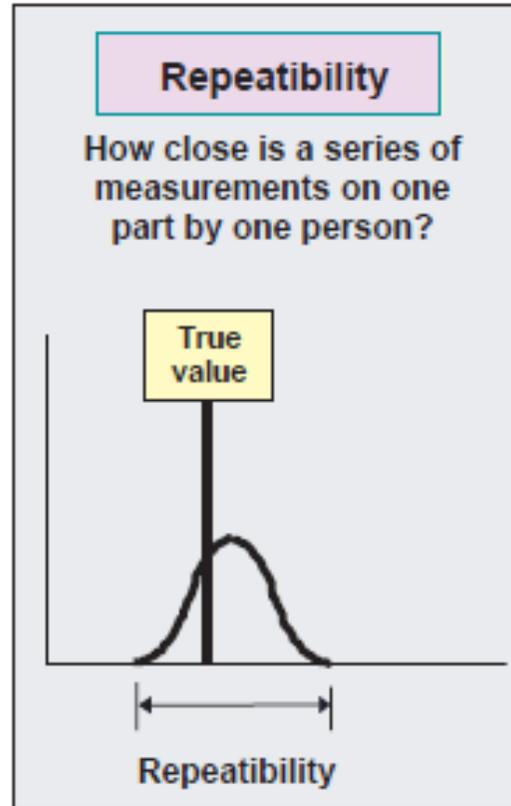
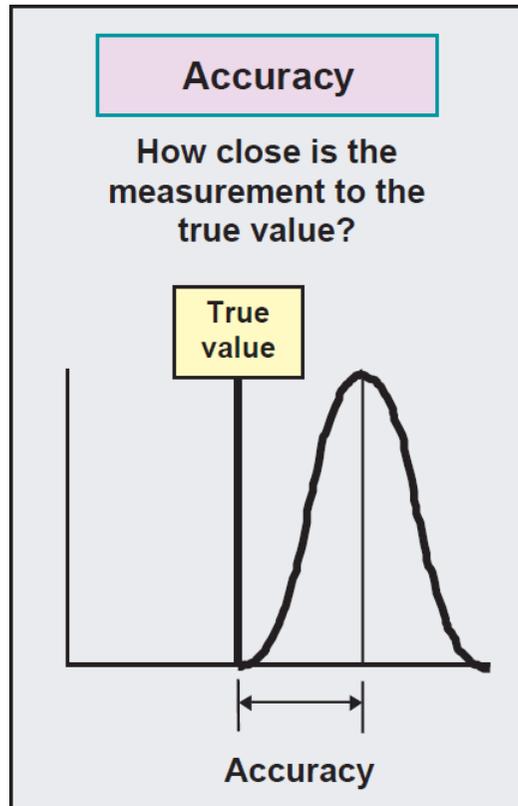
More Accuracy and R&R*

* Repeatability & Reproducibility



Unlocking Measurement Insights for 75 Years

Definitions:



(Source: IPC-TM-650 Number 1.9 Measurement Precision Estimation for Variables Data)

Accuracy Verification using a NIST Traceable Standard



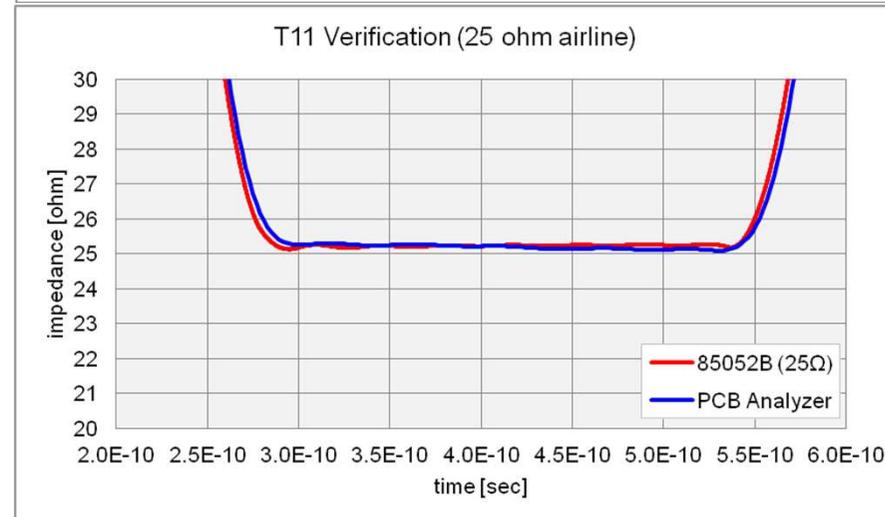
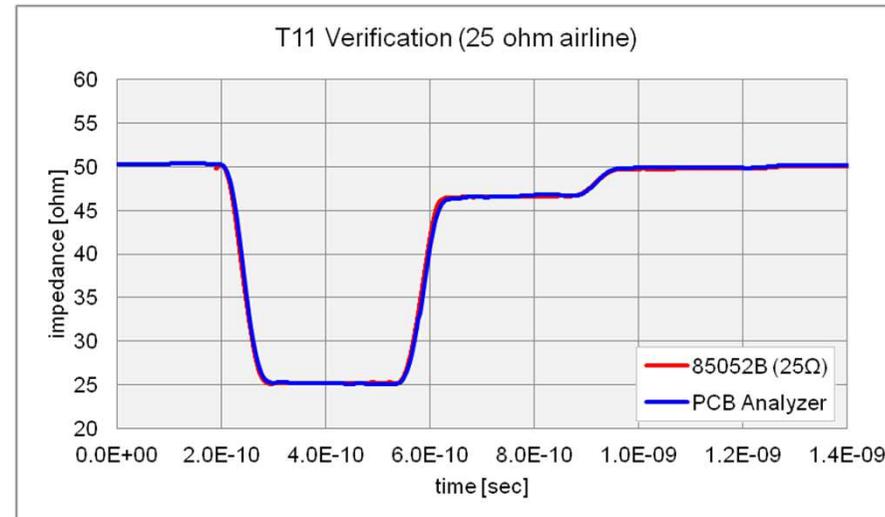
Unlocking Measurement Insights for 75 Years

Measurement results are within 0.1 ohm of 25 ohm airline standard.

DUT: 25 ohm airline
(85052B Verification Kit)



The verification kit includes measurement data and uncertainties which are traceable to National Institute of Standards and Technology (NIST).



R&R Evaluation (Average and Range Method)



Unlocking Measurement Insights for 75 Years

	Single-ended	Differential
R&R	0.010 ohm	0.020 ohm

DUT: R&R Evaluation Board
(unused ports left open)

DUT Length = 22 cm



Test Conditions

- 3 operators
- 7 DUTs
- 3 measurements on each DUT
- Average impedance within 30-70% of the DUT length used for R&R calculations

Error Correction Techniques



Unlocking Measurement Insights for 75 Years



Error correction techniques enables you to measure the true performance of your device, not your measurement system.

No time-domain instrument can surpass the accuracy, sensitivity, noise floor, and autocalibration routines inherent to a network analyzer.

(Source: EDN Oct 12, 2006)

Dedicated GUI for PCB Measurements



Unlocking Measurement Insights for 75 Years

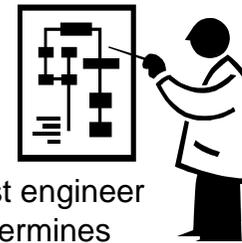
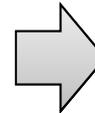


Modes of Operation



Edit Test Mode

- Define test parameters and generate test setup file.

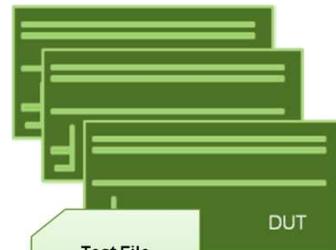


Test engineer determines measurement requirements.

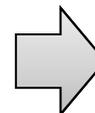


Execute Test Mode

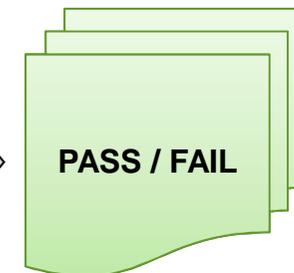
- Recall test setup file and execute test.



Test File
(Instrument configuration, test list, limits, etc ...)



Automated or manual test, typically performed by non-technical operator

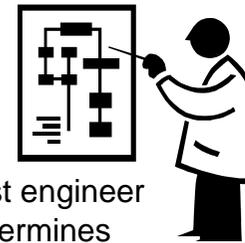


Modes of Operation



Edit Test Mode

- Define test parameters and generate test setup file.

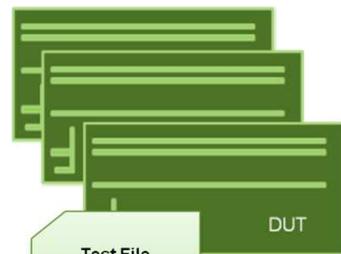


Test engineer determines measurement requirements.

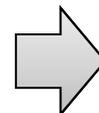


Execute Test Mode

- Recall test setup file and execute test.



Test File
(Instrument configuration, test list, limits, etc ...)



Automated or manual test, typically performed by non-technical operator

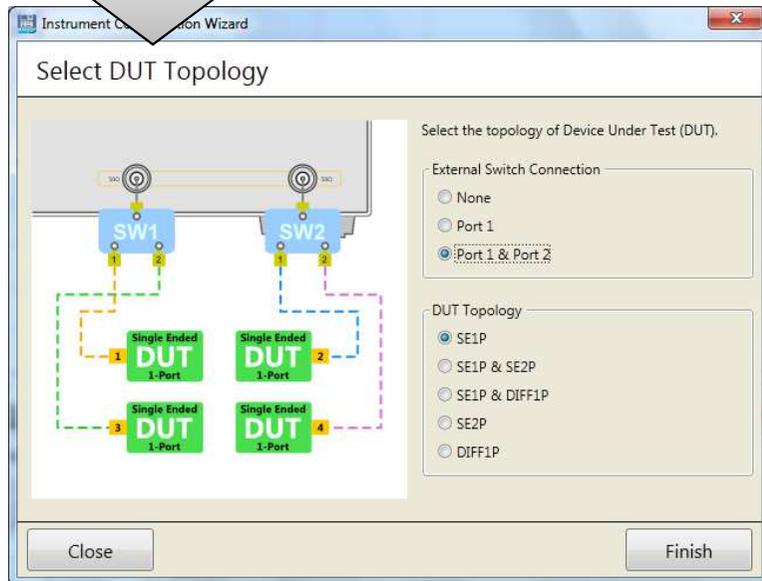
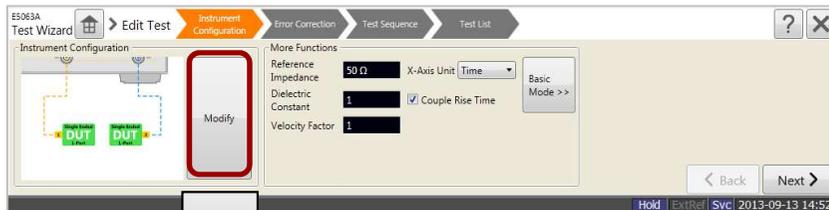


Edit Test Mode > Instrument Configuration



Unlocking Measurement Insights for 75 Years

The E5063A PCB Analyzer provides two ports for measurement. By connecting up to two U1810B USB Coaxial Switches (SPDT), the number of available ports can be extended up to four.



Note:

- When connecting only one switch, the switch must be connected to E5063A Port 1.
- When only one switch is connected and two switch configuration (Port 1 & Port 2) is selected:
 - In the Edit Test mode, a Warning message is generated, but edit test is possible.
 - In the Execute Test mode, an Error message is generated and test execution is not possible.

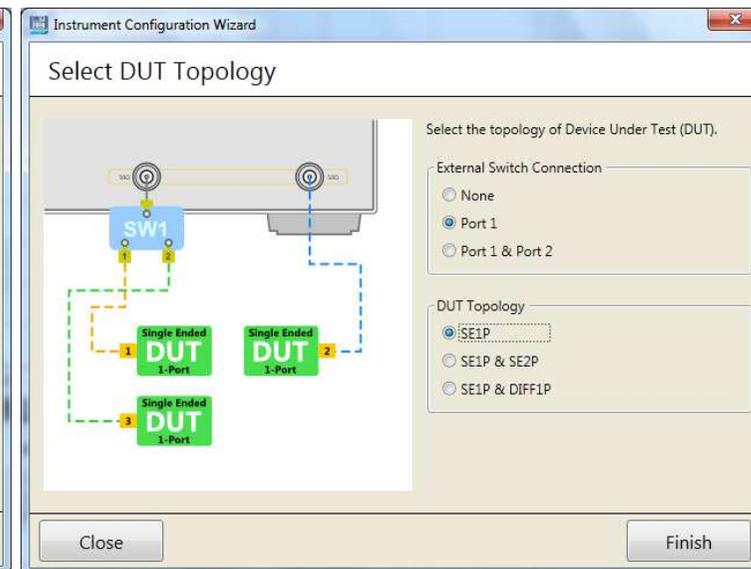
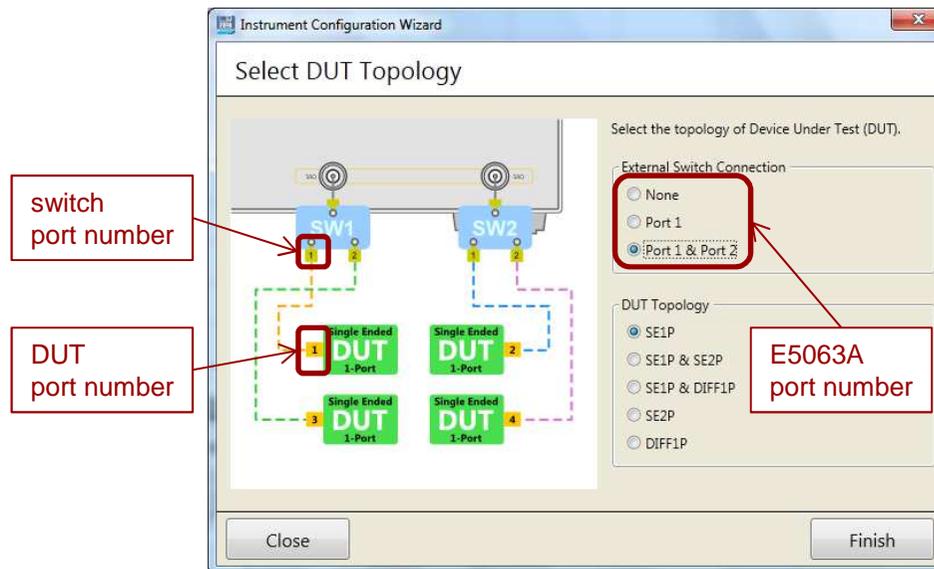
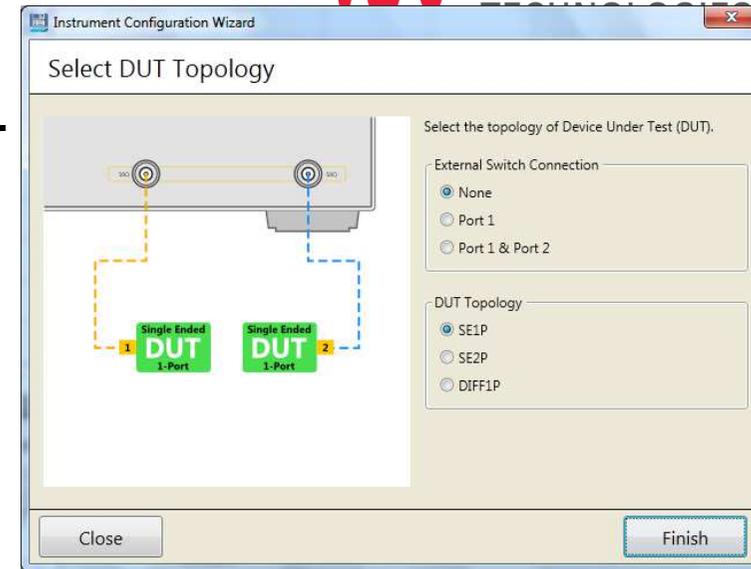
Edit Test Mode > Instrument Configuration



The available DUT Topology selections will depend on the number of switches selected.

Note:

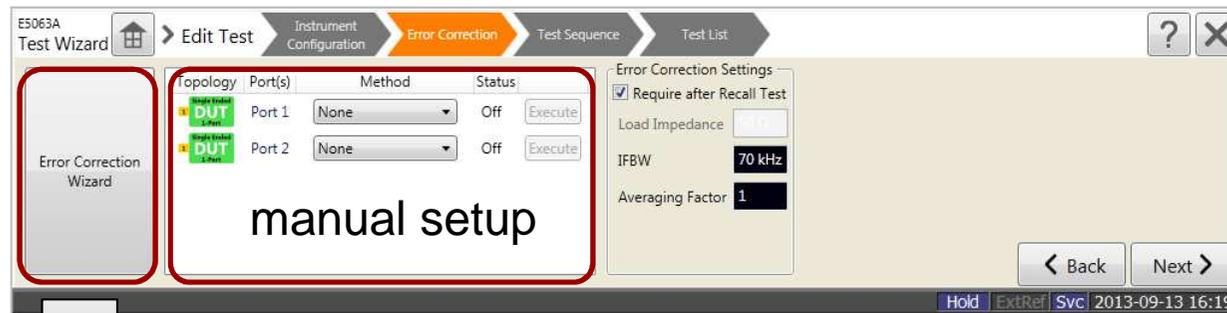
- The switch port number is shown in yellow and the DUT port number is shown in orange.
- The DUT port number is used when defining measurement parameters (ex. TDR on Port 3 is T33).



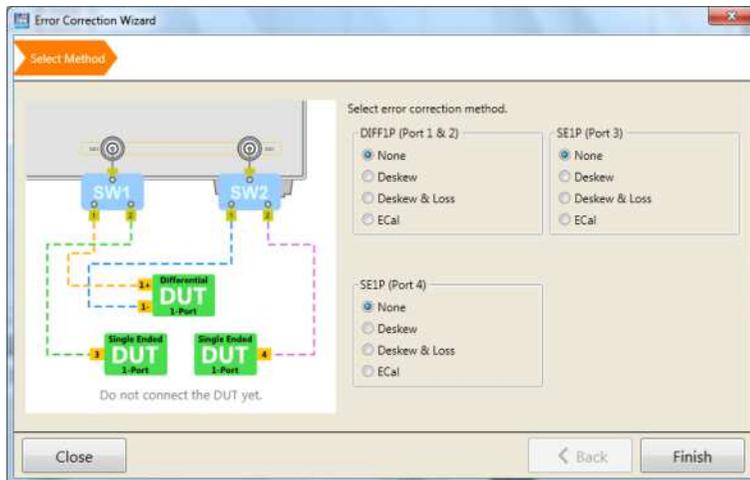
Edit Test Mode > Error Correction



The Error Correction Wizard (recommended) provides a step-by-step guide to perform error correction. Manual setup and execution is also possible by selecting the appropriate method in the Error Correction table.



Wizard



•The following error correction methods are available:

- Deskew
- Deskew and loss compensation
- Full Calibration (ECal)

Why Error Correction?

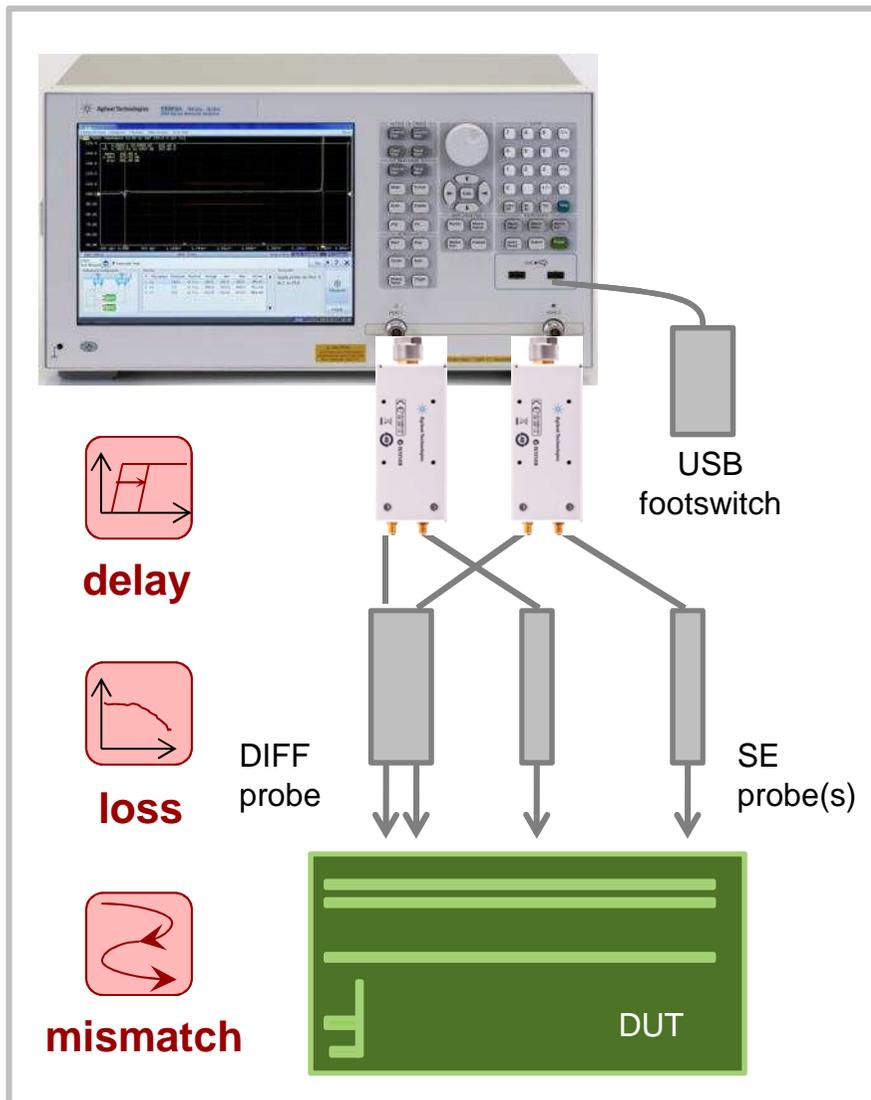


Unlocking Measurement Insights for 75 Years

Measure your device, not your measurement system.

Cables, probes, switches, and fixtures are no longer ideal at today's data rates.

To get the most accurate information about the device under test, you must account for errors introduced by your measurement system, such as delay, loss, and mismatch.



Error Correction Method Comparison

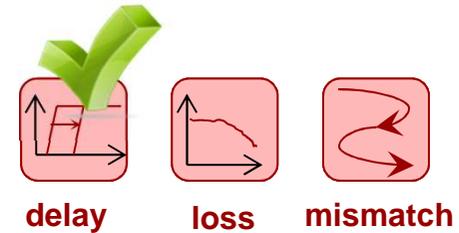


Unlocking Measurement Insights for 75 Years

Two common types of error correction methods (FAST):

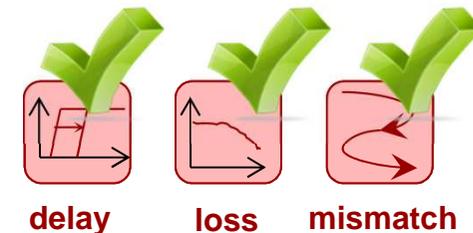
Deskew

- Commonly used in time domain instruments
- Simple to perform
- Only corrects for delay

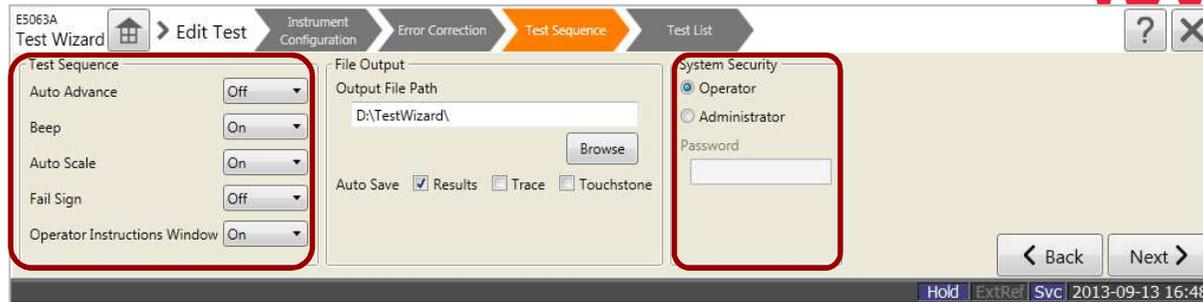


Full calibration (ECal)

- Commonly used in frequency domain instruments
- Requires more standards
- Accounts for all major sources of error



Edit Test Mode > Test Sequence



Test Sequence

- Auto Advance

On
On Pass
Off

- Beep

On
On Pass
On Fail
Off

- Auto Scale

On
Off

- Fail Sign

On
Off

- Operator Inst Window

On
Off

System Security

- Operator: access to Edit Test mode without password.



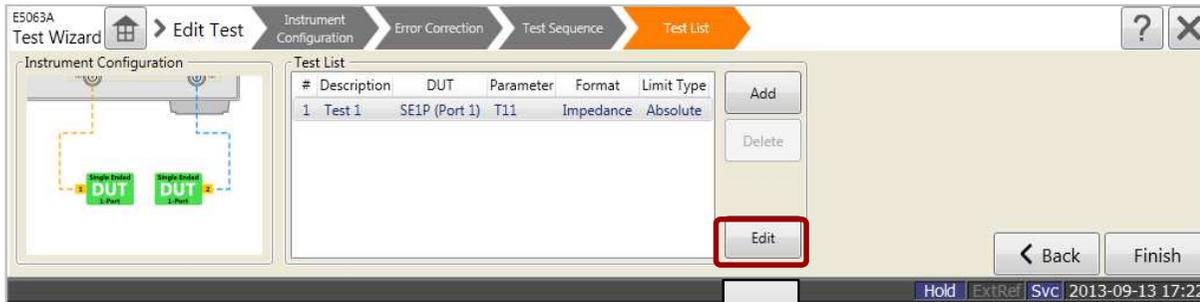
- Administrator: password required to enter Edit Test Mode



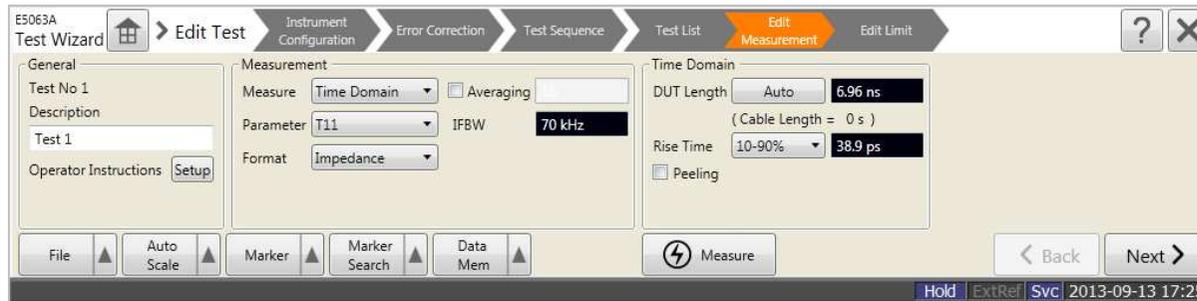
Edit Test Mode > Test List



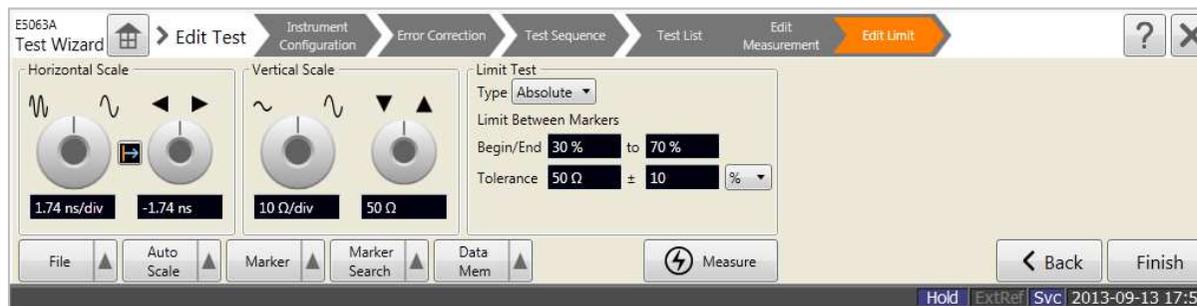
Unlocking Measurement Insights for 75 Years



•Edit Measurement



•Edit Limit

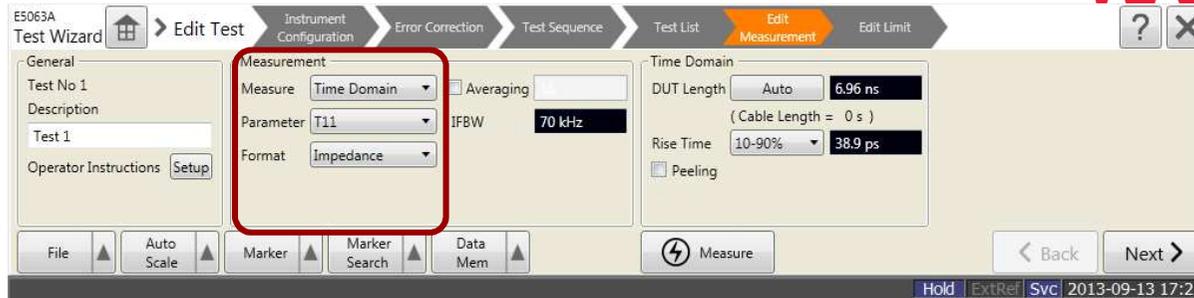


Edit Test Mode > Test List > Edit Measurement

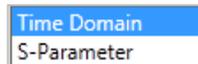


KEYSIGHT
TECHNOLOGIES

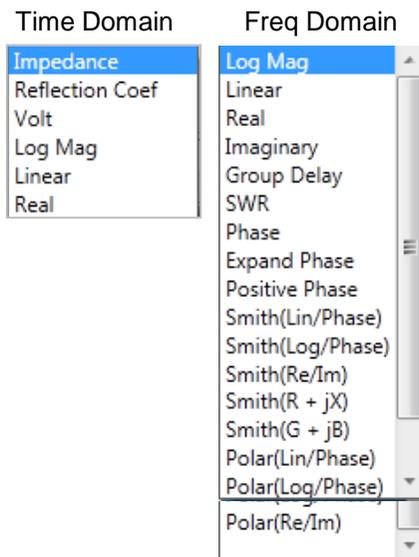
Measurement Insights for 75 Years



•Measure



•Format



•Parameters

Available Not Available

Topology: SE1P

T11	T12	T13	T14
T21	T22	T23	T24
T31	T32	T33	T34
T41	T42	T43	T44

Topology: SE2P

T11	T12	T13	T14
T21	T22	T23	T24
T31	T32	T33	T34
T41	T42	T43	T44

Topology: DIFF1P

Tdd11	Tdd12	Tdc11	Tdc12
Tdd21	Tdd22	Tdc21	Tdc22
Tcd11	Tcd12	Tcc11	Tcc12
Tcd21	Tcd22	Tcc21	Tcc22

Note:

- Available parameters will depend on the selected instrument configuration. (ex. For Port 1 (one switch) and SE1P topology, T44 is not available.)
- Equivalent S-parameters are available when frequency domain is selected.



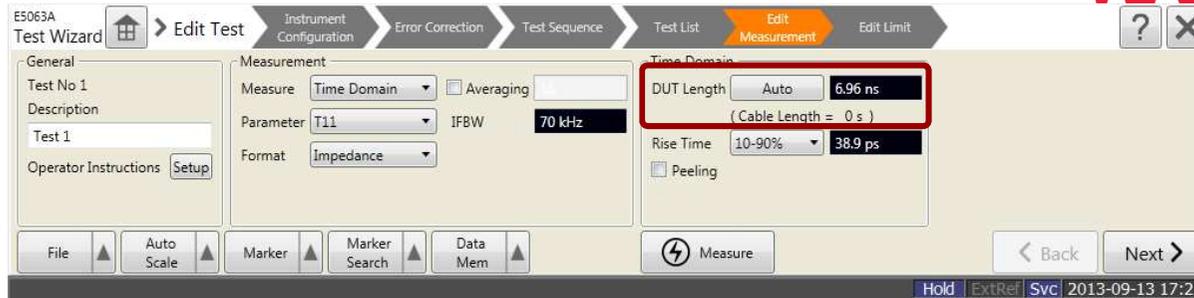
Agilent Technologies

Edit Test Mode > Test List > Edit Measurement



KEYSIGHT
TECHNOLOGIES

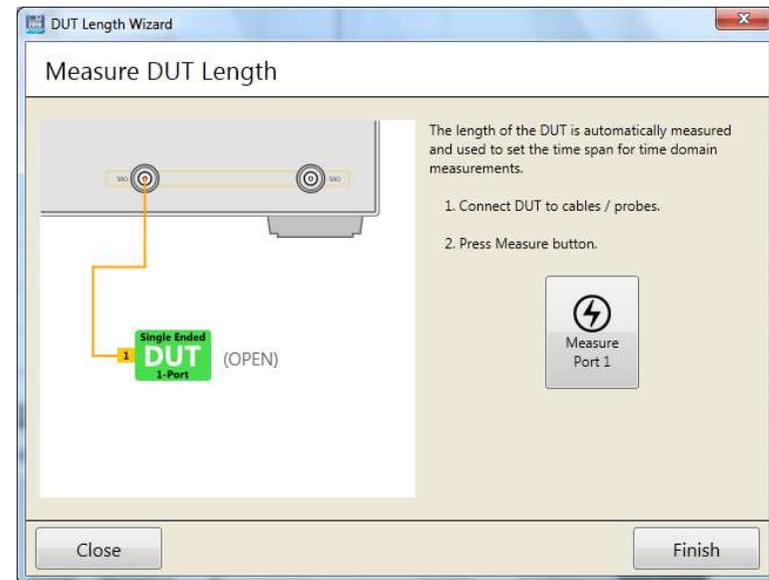
Measurement Insights for 75 Years



•DUT Length

The DUT Length Wizard (recommended) provides an automatic measurement of the DUT length. Manual entry is also possible using the numeric entry box.

The DUT length setting is used to set the optimum time span for time domain measurements.

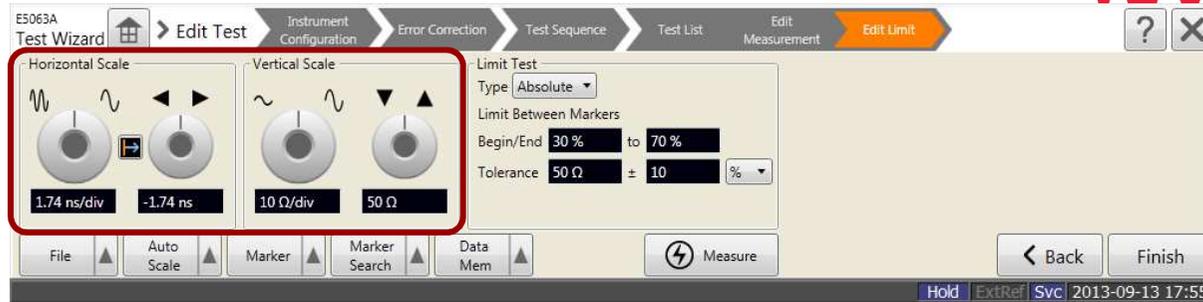


Agilent Technologies

Edit Test Mode > Test List > Edit Limit



Measurement Insights for 75 Years

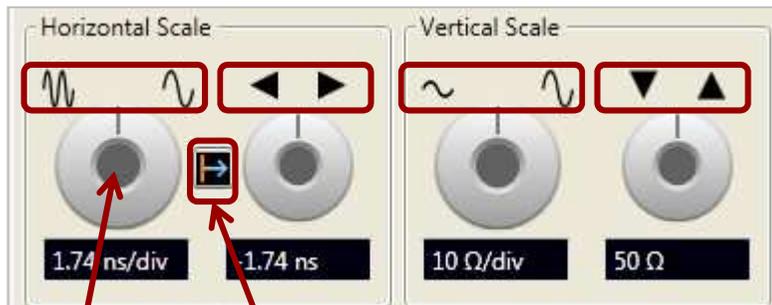


increase / decrease scale

(1-2-5 step) left right

increase / decrease scale

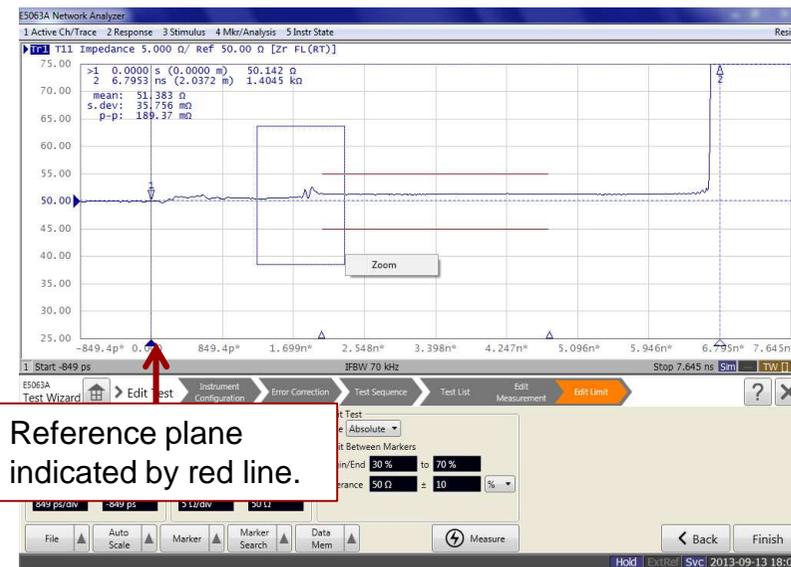
(1-2-5 step) down up



Reference position (left edge or center)

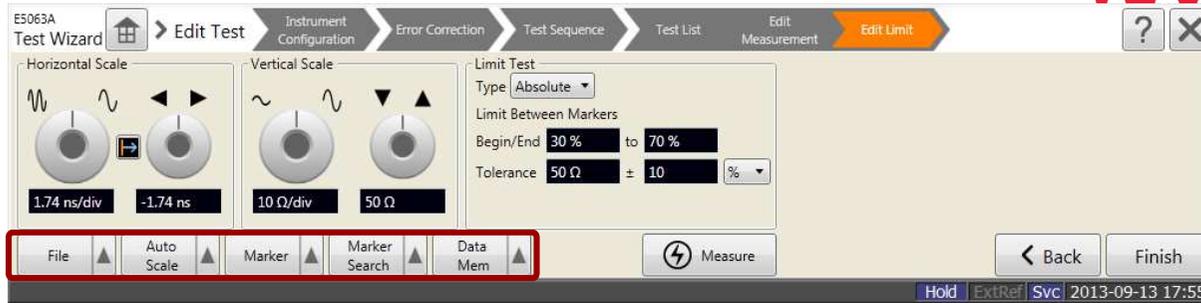
Click on software knobs to enable mouse wheel.

- By specifying an area with the mouse, it is possible to zoom in on specific sections of the response.

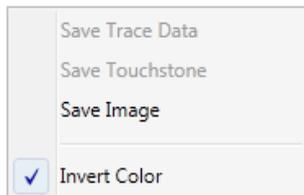


Reference plane indicated by red line.

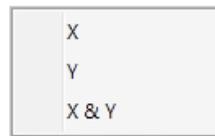
Edit Test Mode > Test List > Edit Limit



•File



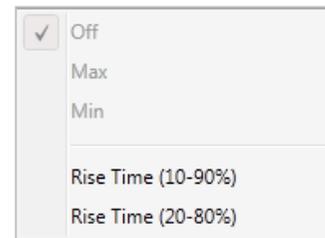
•Auto Scale



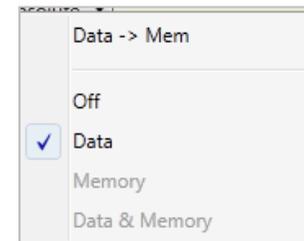
•Marker



•Marker Search



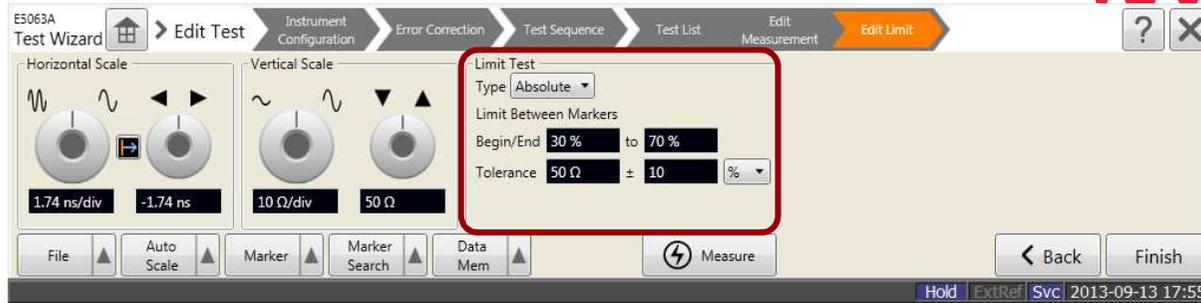
•Data Mem



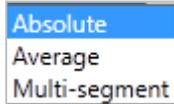
Note:

Markers 1 and 2 are reserved for defining the measurement range.

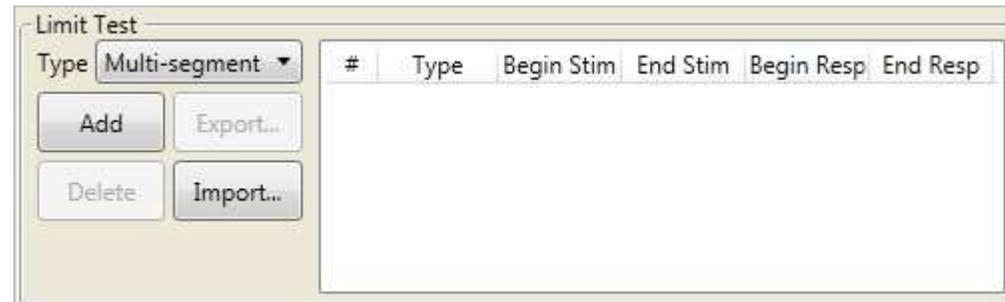
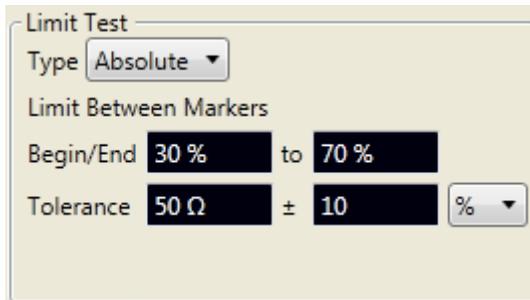
Edit Test Mode > Test List > Edit Limit



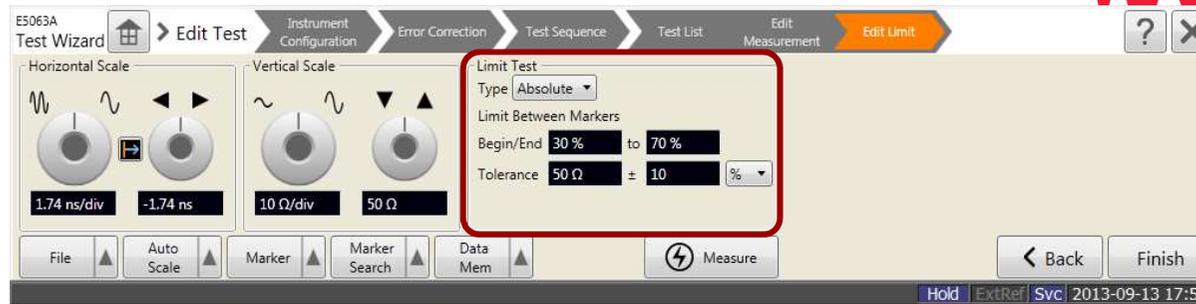
•Type



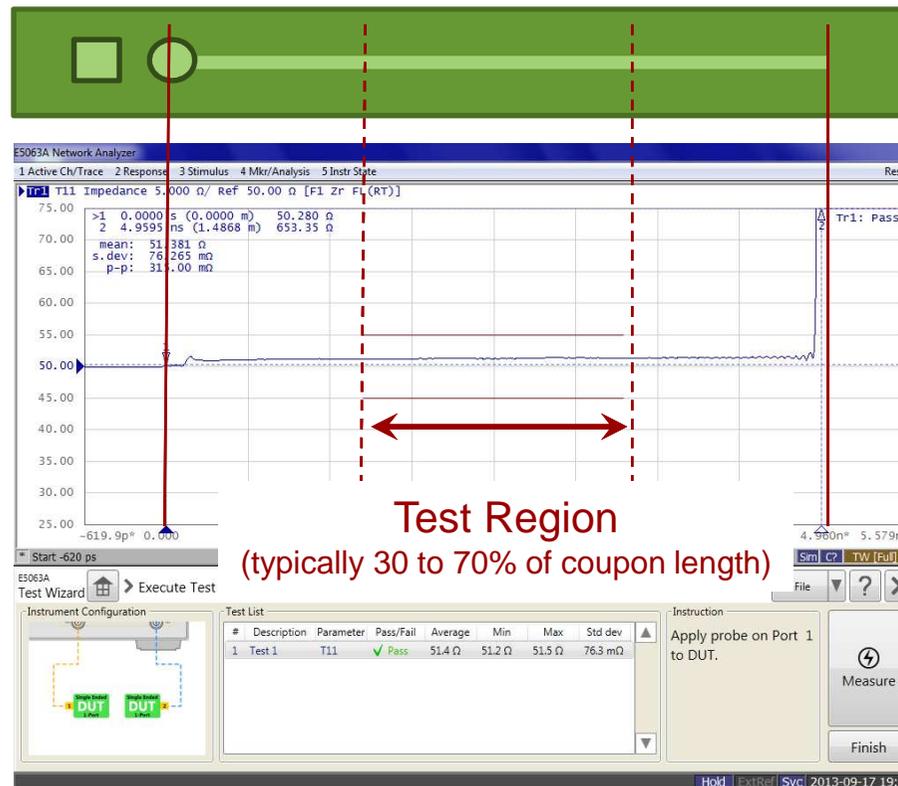
- Absolute limit test will perform pass/fail judgment on each point in the defined test area.
- Average limit test will perform pass/fail judgment on the average impedance value in the defined test area.
- Multi-segment limit test will perform pass/fail judgment based on the limit line defined in the limit table.



Edit Test Mode > Test List > Edit Limit



- The **Limit Between Markers** feature enables users to specify the length of the trace to be tested.

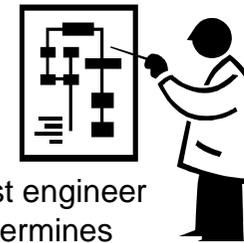


Modes of Operation



Edit Test Mode

- Define test parameters and generate test setup file.



Test engineer determines measurement requirements.



Execute Test Mode

- Recall test setup file and execute test.



Automated or manual test, typically performed by non-technical operator



Execute Test Mode



Measurement Insights for 75 Years

#	Description	Parameter	Pass/Fail	Average	Min	Max	Std dev
1	L1/DIFF100	Tdd11	✓ Pass	100 Ω	100 Ω	101 Ω	128 mΩ
2	L1/SE50	T33	✓ Pass	50.1 Ω	49.8 Ω	50.3 Ω	94.9 mΩ
3	ANT	S44	✓ Pass	0 dB	0 dB	0 dB	0 dB

Operator Instructions

Customize operator prompts as appropriate for your application.

Operator Instruction Setup

Instruction

Default
Apply probe on Port 1 & 2 to DUT.

Text Message

Picture
C:\Program Files (x86)\Agilent\E5063\TestWizard\NoImage.p

Preview

Apply probe on Port 1 & 2 to DUT.

Close

Saving Test Results

All test results are displayed on screen in waveform and statistical format for real-time analysis. Results can also be saved to file for later inspection.

Save Test Result

Result

PASS

Path to Files

Serial Number
001

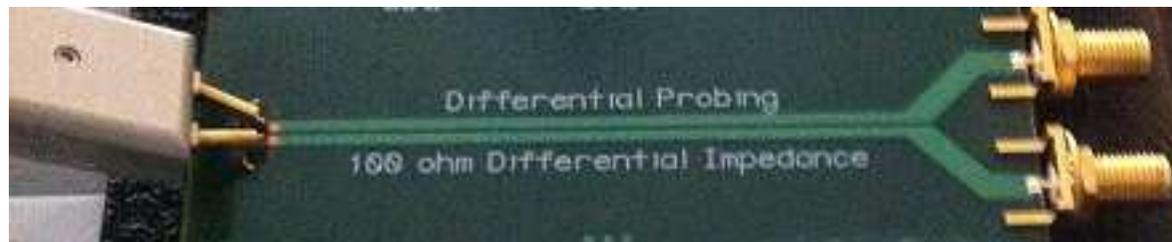
Folder Name
D:\TestWizard\001\

Close Finish

Demo: Tdd11 and Sdd11



Unlocking Measurement Insights for 75 Years



AGENDA



Unlocking Measurement Insights for 75 Years

- Traditional PCB Measurements
- PCB Market Trends
- Dedicated VNA for PCB Measurements
- **Summary & Closure**

THANK YOU !



Download the slides here!
[ftp.agilent.com/Users/Spain](ftp://ftp.agilent.com/Users/Spain)

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contactcenter_spain@agilent.com
91 631 3300